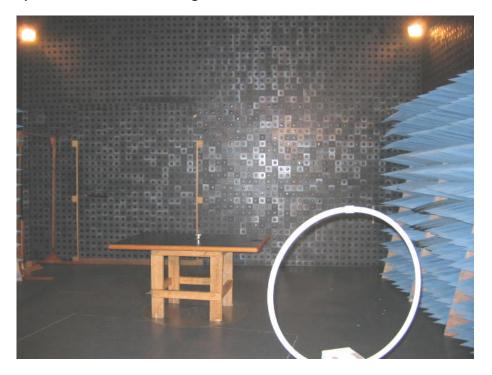


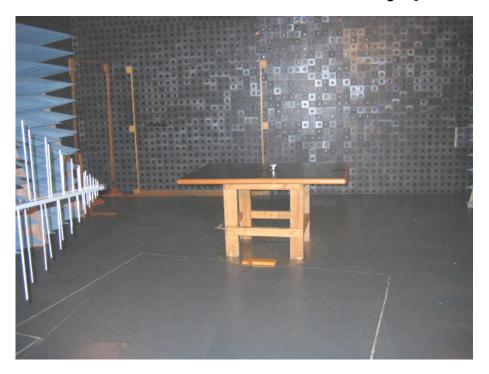
Photograph No.1 Test setup for 6 dB bandwidth measurements and for carrier field strength measurements



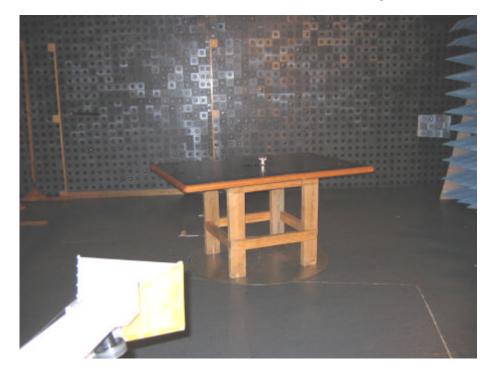
Photograph No.2 Setup for spurious emission field strength measurements in the anechoic chamber below 30 MHz



## Photograph No.3 Setup for spurious emission field strength measurements in the anechoic chamber from 30 to 1000 MHz and for radiated emission measurements according to §15.109



Photograph No.4 Setup for spurious emission field strength measurements in anechoic chamber above 1000 MHz and for radiated emission measurements according to §15.109





Photograph No.5 Setup for spurious emission field strength measurements at OATS above 1000 MHz